2018 IEEE 21st International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS 2018)

Budapest, Hungary 25-27 April 2018



IEEE Catalog Number: ISBN:

CFP18DDE-POD 978-1-5386-5755-3

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 IEEE Catalog Number:
 CFP18DDE-POD

 ISBN (Print-On-Demand):
 978-1-5386-5755-3

 ISBN (Online):
 978-1-5386-5754-6

ISSN: 2334-3133

Additional Copies of This Publication Are Available From:

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2018 21st IEEE **International Symposium** on Design and Diagnostics of Electronic Circuits and **Systems**

DDECS 2018

Table of Contents

Foreword to the DDECS 2018 Symposium .ix
Poster Session 1
Reliability-Aware Multi-Vth Domain Digital Design Assessment .1
Heap Queue: A Novel Efficient Hardware Architecture of MIN/MAX Queues for Real-Time Systems .5
Lukas Kohutka (Slovak University of Technology) and Viera Stopjakova (Slovak University of Technology)
Flip-Flop SEUs Mitigation through Partial Hardening of Internal Latch and Adjustment of Clock Duty Cycle .9.
Yuanqing Li (IHP), Anselm Breitenreiter (IHP), Marko Andjelkovic (IHP), Oliver Schrape (IHP), and Milos Krstic (IHP)
Nonlinear Binary Codes and Their Utilization for Test .1.5. Ondreg Novak (Technical University in Liberec)
Replication-Based Deterministic Testing of 2-Dimensional Arrays with Highly Interrelated Cells .21
Siavoosh Payandeh Azad (Tallinn University of Technology), Adeboye Stephen Oyeniran (Tallinn University of Technology), and Raimund Ubar (Tallinn University of Technology)
Contribution to Automated Generating of System Power-Management Specification .27
A Rare Event Based Yield Estimation Methodology for Analog Circuits .33

Session 1: Analog Design

A Novel TFET 8T-SRAM Cell with Improved Noise Margin and Stability .39...... Seyed Hamid Fani (Ferdowsi University of Mashhad), Ali Peiravi (Ferdwosi University of Mashhad), Hooman Farkhani (Aarhus University), and Farshad Moradi (Aarhus University) Daniel Arbet (Slovak University of Technology), Martin Kovac (Slovak University of Technology), Lukas Nagy (Slovak University of Technology), Viera Stopjakova (Slovak University of Technology), and Michal Šovcík (Slovak University of Technology) Design and Performance Analysis of Ultra-Low Voltage Rail-to-Rail Comparator in 130 nm CMOS Technology .51. Lukas Nagy (Slovak University of Technology), Daniel Arbet (Slovak University of Technology), Martin Kovac (Slovak University of Technology), Miroslav Potocny (Slovak University of Technology), and Viera Stopjakova (Slovak University of Technology) Session 2: System Design Superpixel Accelerator for Computer Vision Applications on Arria 10 SoC .55..... Amila Akagic (University of Sarajevo), Emir Buza (University of Sarajevo), Razija Turcinhodzic (University of Sarajevo), Hana Haseljic (University of Sarajevo), Noda Hiroyuki (Keio University), and Hideharu Amano (Keio University) Heuristic for Page-Based Incremental Reprogramming of Wireless Sensor Nodes .61..... Kai Lehniger (IHP), Stefan Weidling (IHP), and Mario Schölzel (IHP) QoSinNoC: Analysis of QoS-Aware NoC Architectures for Mixed-Criticality Applications .67...... Serhiy Avramenko (Politecnico di Torino), Siavoosh Payandeh Azad (Tallinn University of Technology), Stefano Esposito (Politecnico di Torino), Behrad Niazmand (Tallinn University of Technology), Massimo Violante (Politecnico di Torino), Jaan Raik (Tallinn University of Technology), and Maksim Jenihhin (Tallinn University of Technology) **Session 3: Digital Circuit Test** Tuning Stochastic Space Compaction to Faster-than-at-Speed Test .7.3..... Alexander Sprenger (University of Paderborn) and Sybille Hellebrand (University of Paderborn) Constraint-Based Pattern Retargeting for Reducing Localized Power Activity During Testing 79.... Harshad Dhotre (University of Bremen), Stephan Eggersgluss (Mentor Graphics Development GmbH), Rolf Drechsler (University of Bremen & DFKI GmbH), Mehdi Dehbashi (Infineon Technologies), and Ulrike Pfannkuchen (Infineon Technologies) On the Comparison of Different ATPG Approaches for Approximate Integrated Circuits .85...... Marcello Traiola (LIRMM), Arnaud Virazel (LIRMM), Patrick Girard (LIRMM), Mario Barbareschi (DIETI - University of Naples Federico II), and Alberto Bosio (LIRMM)

Poster Session 2

An Integrated Phase Shifting Frequency Synthesizer for Active Electronically Scanned	
Arrays	91
Modeling and Accelerated Mixed-Signal Simulation of a Control System	95
Natural Language Based Power Domain Partitioning	101
Synthesis of Finite State Machines on Memristor Crossbars Umberto Ferrandino (DIETI - University of Naples Federico II), Marcello Traiola (LIRMM), Mario Barbareschi (DIETI - University of Naples Federico II), Antonino Mazzeo (DIETI - University of Naples Federico II), Petr Fiser (Czech Technical University of Prague), and Alberto Bosio (LIRMM)	107
2.4 GHz LC-VCO with Improved Robustness against PVT Using FD-SOI Body Biasing Technique	113
Szymon Reszewicz (Warsaw University of Technology), Krzysztof Siwiec (Warsaw University of Technology), and Witold A. Pleskacz (Warsaw University of Technology)	
Augmenting All Solution SAT Solving for Circuits with Structural Information	117
Design of Low-Bit Robust Analog-to-Digital Converters for Signals with Gaussian Distribution	123
Session 4: Reconfigurability	
An Evolutionary Technique for Reducing the Duration of Reconfigurable Scan Network Test Riccardo Cantoro (Politecnico di Torino), Luigi San Paolo (Politecnico di Torino), Matteo Sonza Reorda (Politecnico di Torino), and Giovanni Squillero (Politecnico di Torino)	129
Intermittent Resistance Fault Detection at Board Level Hassan Ebrahimi (University of Twente) and Hans G. Kerkhoff (University of Twente)	135
Session 5: Reliability	
Using a Duplex Time-to-Digital Converter for Metastability Characterization of an FPGA	141

Session 6: Student Papers

Integrated Sensors for Early Breast Cancer Diagnostics 1.53
Self Vth-Compensating CMOS On-Chip Rectifier for Inductively Powered Implantable Medical Devices .1.58
A Methodology to Verify Digital IP's within Mixed-Signal Systems .1.62
Author Index 167